# **Power MOSFET**

# 20 V/-20 V, 4.6 A/-4.1 A, Complementary, 2x2 mm, WDFN Package

#### **Features**

- Complementary N-Channel and P-Channel MOSFET
- WDFN Package with Exposed Drain Pad for Excellent Thermal Conduction
- Footprint Same as SC-88 Package
- Leading Edge Trench Technology for Low On Resistance
- 1.8 V Gate Threshold Voltage
- Low Profile (< 0.8 mm) for Easy Fit in Thin Environments
- This is a Pb-Free Device

#### **Applications**

- Synchronous DC-DC Conversion Circuits
- Load/Power Management of Portable Devices like PDA's, Cellular Phones and Hard Drives
- Color Display and Camera Flash Regulators

#### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

Paran	Symbol	Value	Unit			
Drain-to-Source Voltage	N-Ch	$V_{DSS}$	20	V		
	P-Ch		-20			
Gate-to-Source Voltage	je	N-Ch	$V_{GS}$	±8.0	V	
		P-Ch				
N-Channel	Steady	$T_A = 25^{\circ}C$	I <sub>D</sub>	3.8	Α	
Continuous Drain Current (Note 1)	State	$T_A = 85^{\circ}C$		2.8		
Ourient (Note 1)	t≤5s	$T_A = 25^{\circ}C$		4.6		
P-Channel	Steady	$T_A = 25^{\circ}C$	I <sub>D</sub>	-3.3	Α	
Continuous Drain Current (Note 1)	State	$T_A = 85^{\circ}C$		-2.4	1	
Ourient (Note 1)	t≤5s	$T_A = 25^{\circ}C$		-4.1		
Power Dissipation (Note 1)	Steady State	T <sub>A</sub> = 25°C	P <sub>D</sub>	1.5	W	
	t≤5s			2.3		
N-Channel	Steady	$T_A = 25^{\circ}C$	$I_{D}$	2.6	Α	
Continuous Drain Current (Note 2)	State	T <sub>A</sub> = 85°C		1.9		
P-Channel	Steady	$T_A = 25^{\circ}C$	I <sub>D</sub>	-2.3	Α	
Continuous Drain Current (Note 2)	State	T <sub>A</sub> = 85°C		-1.6		
Power Dissipation (Note 2)	Steady State	T <sub>A</sub> = 25°C	P <sub>D</sub>	0.71	W	
Pulsed Drain Current	N-Ch	t <sub>p</sub> = 10 μs	$I_{DM}$	18	Α	
	P-Ch			-20		
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>STG</sub>	–55 to 150	°C	
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- Surface Mounted on FR4 Board using 1 in sq pad size (Cu area = 1.127 in sq [2 oz] including traces).
- Surface Mounted on FR4 Board using the minimum recommended pad size of 30 mm<sup>2</sup>, 2 oz Cu.



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V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub> MAX	I <sub>D</sub> MAX
	65 m $\Omega$ @ 4.5 V	3.8 A
N-Channel 20 V	85 mΩ @ 2.5 V	2.0 A
	120 mΩ @ 1.8 V	1.7 A
D. Obsessed	100 mΩ @ –4.5 V	-4.1 A
P-Channel -20 V	135 mΩ @ –2.5 V	-2.0 A
	200 mΩ @ –1.8 V	-1.6 A

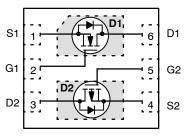
# D2 D1 MARKING DIAGRAM WDFN6 CASE 506AN D1 JM M

JM = Specific Device Code M = Date Code

= Pb-Free Package

(Note: Microdot may be in either location)

#### **PIN CONNECTIONS**



(Top View)

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NTLJD3119CTAG	WDFN6 (Pb-Free)	3000/Tape & Reel
NTLJD3119CTBG	WDFN6 (Pb-Free)	3000/Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

#### THERMAL RESISTANCE RATINGS

Parameter	Symbol	Max	Unit
SINGLE OPERATION (SELF-HEATED)			
Junction-to-Ambient - Steady State (Note 3)	$R_{ hetaJA}$	83	
Junction-to-Ambient - Steady State Min Pad (Note 4)	$R_{ hetaJA}$	177	°C/W
Junction-to-Ambient – t ≤ 5 s (Note 3)	$R_{ hetaJA}$	54	
DUAL OPERATION (EQUALLY HEATED)			
Junction-to-Ambient - Steady State (Note 3)	$R_{ hetaJA}$	58	
Junction-to-Ambient - Steady State Min Pad (Note 4)	$R_{ heta JA}$	133	°C/W
Junction-to-Ambient – t ≤ 5 s (Note 3)	$R_{ heta JA}$	40	

Surface Mounted on FR4 Board using 1 in sq pad size (Cu area = 1.127 in sq [2 oz] including traces).
 Surface Mounted on FR4 Board using the minimum recommended pad size (30 mm², 2 oz Cu).

# **ELECTRICAL CHARACTERISTICS** (T<sub>.I</sub> = 25°C unless otherwise noted)

Parameter	Symbol	N/P	Test Condition	ons	Min	Тур	Max	Unit
OFF CHARACTERISTICS			<u> </u>					
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	N		I <sub>D</sub> = 250 μA	20			V
Ç	, ,	Р	$V_{GS} = 0 V$	I <sub>D</sub> = -250 μA	-20			1
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub> /T <sub>J</sub>	N		l		10.4		mV/°C
Temperature Coefficient		Р				9.95		1
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	N	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 16 V	T <sub>J</sub> = 25 °C			1.0	μΑ
		Р	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = -16 V				-1.0	
		N	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 16 V	T			10	
		Р	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = -16 V	T <sub>J</sub> = 85 °C			-10	
Gate-to-Source Leakage Current	I <sub>GSS</sub>	N	V <sub>DS</sub> = 0 V, V <sub>GS</sub> =				±100	nA
		Р	$V_{DS} = 0 V, V_{GS} =$	±8.0 V			±100	
ON CHARACTERISTICS (Note 5)								
Gate Threshold Voltage	V <sub>GS(TH)</sub>	N		I <sub>D</sub> = 250 μA	0.4	0.7	1.0	V
		Р	$V_{GS} = V_{DS}$	I <sub>D</sub> = -250 μA	-0.4	-0.7	-1.0	
Gate Threshold Temperature	V <sub>GS(TH)</sub> /T <sub>J</sub>	N		l		-3.0		mV/°C
Coefficient		Р				2.44		
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	N	$V_{GS} = 4.5 \text{ V}$ , $I_D = 3.8 \text{ A}$			37	65	mΩ
		Р	$V_{GS}$ = -4.5 V , $I_D$ = -4.1 A			75	100	- -
		N	$V_{GS} = 2.5 \text{ V}$ , $I_D = 2.0 \text{ A}$			46	85	
		Р	$\begin{array}{cccccccccccccccccccccccccccccccccccc$			101	135	
		N				65	120	1
		Р				150	200	1
Forward Transconductance	9FS	N	V <sub>DS</sub> = 10 V, I <sub>D</sub> =	1.7 A		4.2		S
		Р	$V_{DS} = -5.0 \text{ V}$ , $I_{D} =$	= -2.0 A		3.1		
CHARGES, CAPACITANCES AND GA	ATE RESISTAN	ICE			-			-
Input Capacitance	C <sub>ISS</sub>	N		V <sub>DS</sub> = 10 V		271		pF
		Р		V <sub>DS</sub> = -10 V		531		1
Output Capacitance	C <sub>OSS</sub>	N	N f = 1.0 MHz, V <sub>GS</sub> = 0 V	V <sub>DS</sub> = 10 V		72		
		Р		V <sub>DS</sub> = -10 V		91		1
Reverse Transfer Capacitance	C <sub>RSS</sub>	N		V <sub>DS</sub> = 10 V		43		1
		Р		V <sub>DS</sub> = -10 V		56		1
Total Gate Charge	Q <sub>G(TOT)</sub>	N	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 10	V, I <sub>D</sub> = 3.8 A		3.7		nC
		Р	$V_{GS} = -4.5 \text{ V}, V_{DS} = -10 \text{ V}, I_D = -2.0 \text{ A}$			5.5		
Threshold Gate Charge	Q <sub>G(TH)</sub>	N	$V_{GS} = 4.5 \text{ V}, V_{DS} = 10 \text{ V}, I_D = 3.8 \text{ A}$ $V_{GS} = -4.5 \text{ V}, V_{DS} = -10 \text{ V}, I_D = -2.0 \text{ A}$ $V_{GS} = 4.5 \text{ V}, V_{DS} = 10 \text{ V}, I_D = 3.8 \text{ A}$			0.3		1
		Р				0.7		1
Gate-to-Source Charge	Q <sub>GS</sub>	N				0.6		1
		Р	$V_{GS} = -4.5 \text{ V}, V_{DS} = -10$	V, I <sub>D</sub> = -2.0 A		1.0		1
Gate-to-Drain Charge	Drain Charge $Q_{GD}$ N $V_{GS} = 4.5 \text{ V}, V_{DS} = 10 \text{ V},$		V, I <sub>D</sub> = 3.8 A		1.0		1	
		Р	V <sub>GS</sub> = -4.5 V, V <sub>DS</sub> = -10	V, I <sub>D</sub> = -2.0 A		1.4		1

# **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise noted)

Parameter	Symbol	N/P	Test Conditions		Min	Тур	Max	Unit
SWITCHING CHARACTERISTIC	S (Note 6)							
Turn-On Delay Time	t <sub>d(ON)</sub>		V <sub>GS</sub> = 4.5 V, V <sub>DD</sub> = 16 V,			3.8		ns
Rise Time	t <sub>r</sub>	N				4.7		
Turn-Off Delay Time	t <sub>d(OFF)</sub>		$I_D = 1.0 \text{ A}, R_G =$	2.0 Ω		11.1		
Fall Time	t <sub>f</sub>					5.8		
Turn-On Delay Time	t <sub>d(ON)</sub>					5.2		
Rise Time	t <sub>r</sub>	٦ _	$V_{GS} = -4.5 \text{ V}, V_{DD}$	= -10 V,		13.2		
Turn-Off Delay Time	t <sub>d(OFF)</sub>	P	$I_D = -2.0 \text{ A}, R_G =$	2.0 Ω		13.7		
Fall Time	t <sub>f</sub>	1				19.1		
DRAIN-SOURCE DIODE CHAR	ACTERISTICS							
Forward Diode Voltage	$V_{SD}$	N	N V <sub>GS</sub> = 0 V, T <sub>J</sub> = 25 °C	I <sub>S</sub> = 1.0 A		0.69	1.0	V
		P V <sub>GS</sub> = 0 V, T <sub>J</sub> = 25 °C N V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	I <sub>S</sub> = -1.0 A		-0.75	-1.0		
			I <sub>S</sub> = 1.0 A		0.52			
			I <sub>S</sub> = -1.0 A		-0.64			
Reverse Recovery Time	t <sub>RR</sub>	N		I <sub>S</sub> = 1.0 A		10.2		ns
		Р	I <sub>S</sub> = -1.0 A		16.2			
Charge Time	t <sub>a</sub>	N	N	I <sub>S</sub> = 1.0 A		6.0		
		P V <sub>GS</sub> = 0 V,	I <sub>S</sub> = -1.0 A		10.6			
Discharge Time	t <sub>b</sub>	N	$dI_S / dt = 100 A/\mu s$	I <sub>S</sub> = 1.0 A		4.2		
		Р		I <sub>S</sub> = -1.0 A		5.6		
Reverse Recovery Charge	Q <sub>RR</sub>	N		I <sub>S</sub> = 1.0 A		3.0		nC
		Р		I <sub>S</sub> = -1.0 A		5.7		

<sup>5.</sup> Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
6. Switching characteristics are independent of operating junction temperatures.

# $\textbf{TYPICAL PERFORMANCE CURVES - N-CHANNEL} \ (T_J = 25^{\circ}\text{C unless otherwise noted})$

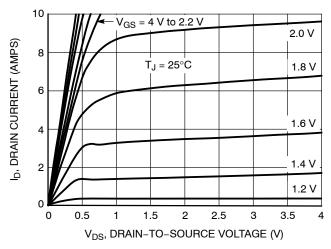


Figure 1. On-Region Characteristics

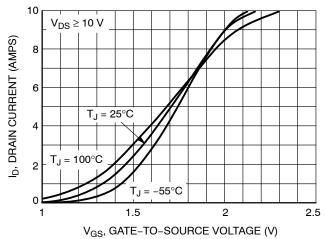


Figure 2. Transfer Characteristics

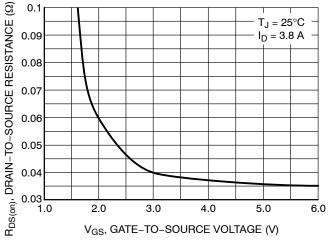


Figure 3. On-Resistance versus Drain Current

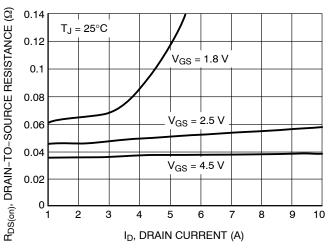


Figure 4. On-Resistance versus Drain Current and Gate Voltage

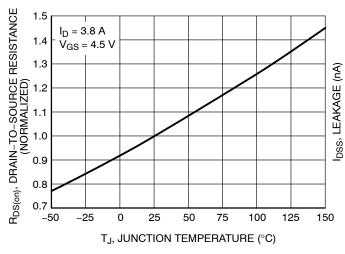


Figure 5. On–Resistance Variation with Temperature

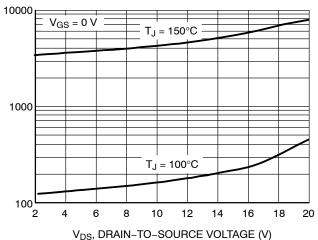
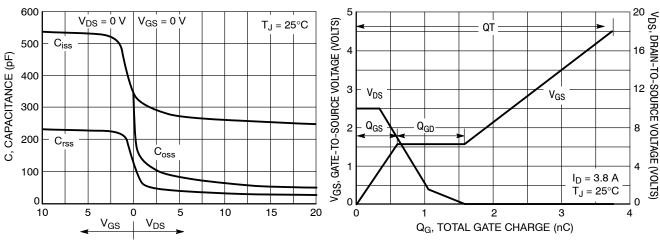


Figure 6. Drain-to-Source Leakage Current versus Voltage

# TYPICAL PERFORMANCE CURVES - N-CHANNEL (T<sub>J</sub> = 25°C unless otherwise noted)



GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (V)

Figure 7. Capacitance Variation

Figure 8. Gate-To-Source and Drain-To-Source Voltage versus Total Charge

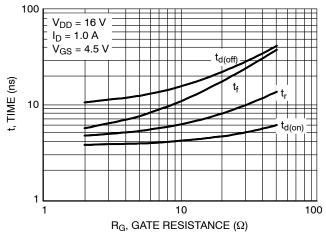


Figure 9. Resistive Switching Time Variation versus Gate Resistance

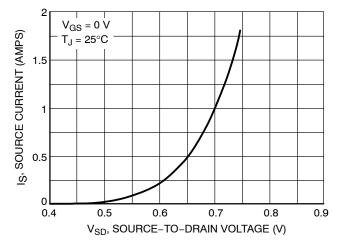


Figure 10. Diode Forward Voltage versus Current

# TYPICAL PERFORMANCE CURVES - P-CHANNEL (T<sub>J</sub> = 25°C unless otherwise noted)

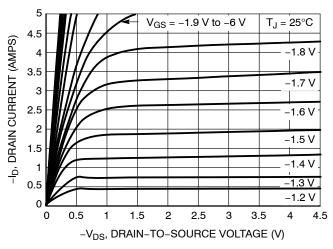
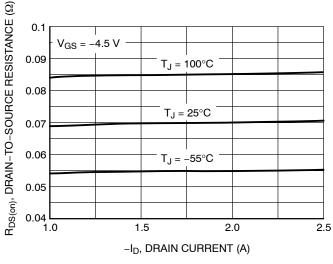


Figure 11. On-Region Characteristics

Figure 12. Transfer Characteristics



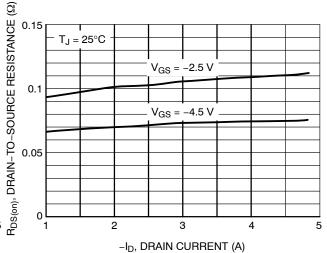
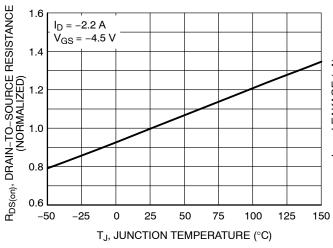


Figure 13. On–Resistance versus Drain Current

Figure 14. On–Resistance versus Drain Current and Gate Voltage





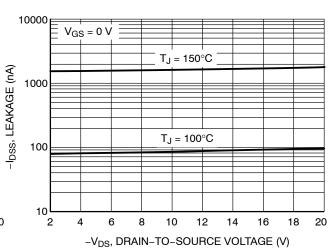
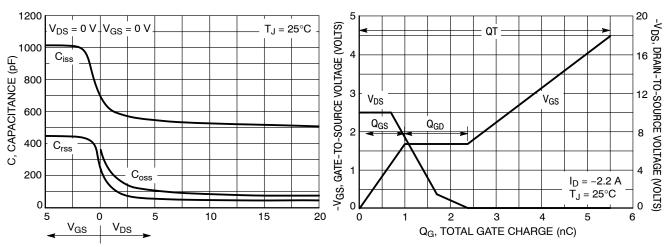


Figure 16. Drain-to-Source Leakage Current versus Voltage

# TYPICAL PERFORMANCE CURVES – P-CHANNEL ( $T_J = 25^{\circ}C$ unless otherwise noted)



GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (V)

Figure 17. Capacitance Variation

Figure 18. Gate-To-Source and Drain-To-Source
Voltage versus Total Charge

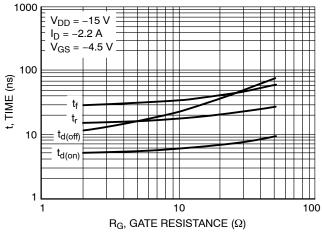


Figure 19. Resistive Switching Time Variation versus Gate Resistance

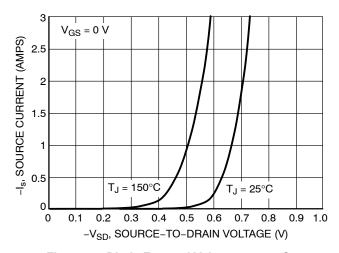


Figure 20. Diode Forward Voltage versus Current

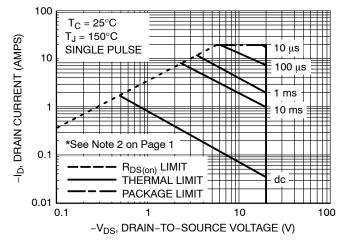


Figure 21. Maximum Rated Forward Biased Safe Operating Area

# TYPICAL PERFORMANCE CURVES ( $T_J = 25^{\circ}$ C unless otherwise noted)

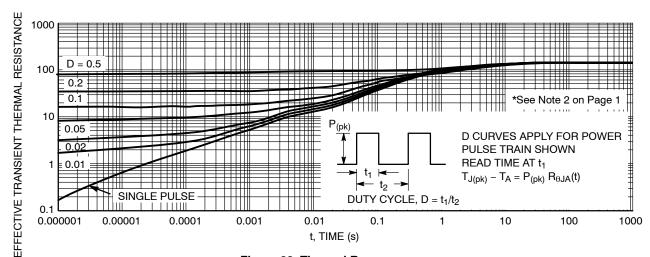
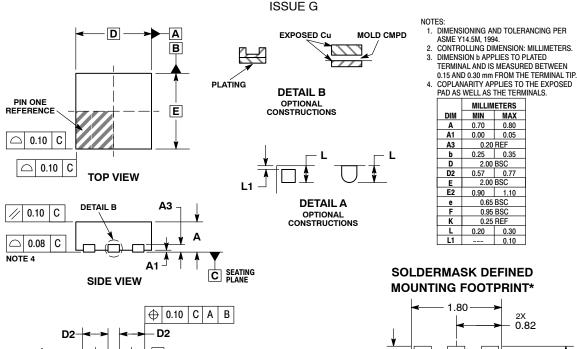
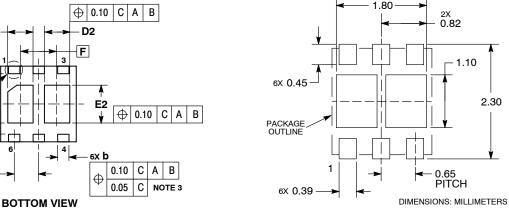


Figure 22. Thermal Response

#### PACKAGE DIMENSIONS

#### WDFN6 2x2, 0.65P CASE 506AN





\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

MILLIMETERS

MIN MAX 0.70

0.00 0.05

0.20 REF 0.25 0.35 2.00 BSC

0.65 BSC

0.95 BSC 0.25 REF 0.20 0.30 0.10

0.57 0.77 2.00 BSC 0.90 1.10

0.80

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